

ABSTRACT OF THE DISCLOSURE

A method of measuring luminance of an image display apparatus, a method of manufacturing the same, and a method and an apparatus for adjusting characteristics of the same, in which accuracy of measurement is improved while reducing time for measuring luminance of a pixel are provided. A plurality of devices that are not adjacent to each other (for example the devices of the same color out of R, G, and B) are selected and illuminated simultaneously, and luminance is measured for each of them. Based on measured luminance, the electron-emitting characteristics of the respective electron-emitting devices are adjusted based on measured luminance.